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Application/Control	No.

Applicant(s)/Patent under Reexamination
KO ET AL.

09/852,607 Examiner

Art Unit

Stephen Bylciw

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SEARCHED				
Class	Subclass	Date	Examiner	
705	7	5/6/2005	SB	
705	28	5/6/2005	SB	
705	8	5/27/2005	SB	
705	10	5/27/2005	SB	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East search (see attached)	5/6/2005	SB
Dialog search (see attached)	5/27/2005	SB
Periodical search: "Management Science" and "IEEE Trans For Semi Manufacturing"	5/27/2005	SB